

future's in the making

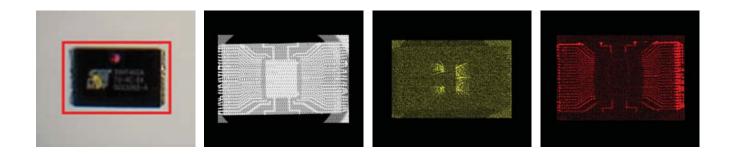
XROS MF30 X-ray analytical microscope-microprobe



XROS MF30 – laboratory x-ray microscope-microprobe for studies of the objects by the methods of the optical microscopy, radiography, local element XRF microanalysis with possibility of the element mapping.

Instrument features:

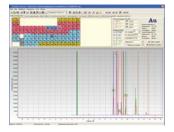
- microfocus x-ray tube
- polycapillary lens for making of an x-ray probe with the variable size
- set of primary radiation filters
- video-camera for selection of the analysis area
- optical digital microscope for investigation of the analysis area
- optical microscope axis combined with an x-ray probe axis
- automated system for selection of the work distance
- automated X, Y-coordinate sample stage for positioning and scanning of the analysis area
- automated movement of the analytical unit along Z axis
- detector for radiographic studies
- silicon drift detector for local XRF analysis
- vacuumized measuring chamber for the analysis of light elements
- built-in autonomous system for water cooling of X-ray tube

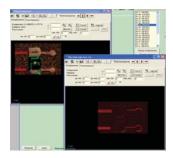


Software:

- system control
 high-voltage generator
 sample and beam positioning
 vacuum
- local elemental analysis and elemental mapping calibration with single certified sample calibration curve with several certified samples determination of energy and intensities of characteristic lines gualitative and semi-guantitative analysis (fundamental parameter method) spectra comparing and searching for analogs from the spectra library element mapping of user-defined sample area spectra and mapping results storing to data file comparison, subtraction, normalization of the stored spectra overlay spectra mapping image results on optical and radiographic images automatic analysis at user-defined points of sample radiography digital brightness and contrast control zooming measurement of distance between image points logging and data storage storing images in a database saving measurement results and export to other Windows programs digitized images record to external media images and protocols printing



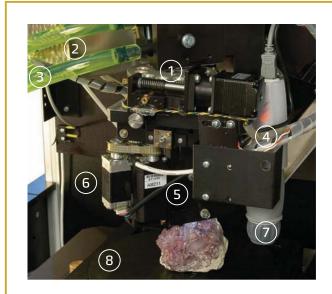




Design:

Moving along Z axis with an accuracy of 12 µm





- block of primary radiation changeable 1 filters (12 filters)
- 2 x-ray tube
- built-in water cooling system
- 3 4 silicon drift detector
- 5 review video camera
- 6 optical microscope axis combined with the axis of the microprobe (automatic adjustment of sharpness)
- 7 optical microscope (manual adjustment of sharpness)
- 8 sample X,Y – stage with an accuracy of 10 µm

Configuration:

Beam source	
Microfocus X-ray tube:	
X-ray tube max. voltage	45 kV
X-ray tube max. power	500 W
anode material	Mo, other by request
Polycapillary lens for x-ray beamforming	
with a variable size of beam	
X-ray beam diameter	30-1 000 μm
Set of primary beam filters	Zr, Ti, Mo, Ag, Al, Cu, Cl

Optical study	
Optical digital microscope:	
• max. zoom	200x

Sample positioning and mapping Video camera to select the area of analysis Optical microscope combined with the axis of the X-ray probe to control the area of analysis				
			Sample and probe moving system:	
			 automated system for the working distance selection analytical unit moving along Z axis Z positioning accuracy automated stage for XY object positioning and scanning over a user-defined sample area 	12 μm
XY positioning accuracy	10 μm			
• max. scan area	150x150 mm			
sample max. size	300x210x100 mm			
sample max. weight	1 kg			

X-ray fluorescence analysis

Energy-dispersive semiconductor detector for local elemental analysis:		
• silicon drift detector (SDD)		
- energy resolution of the detector on the Mn line $K\alpha$	<150 eV	
spectral range	1 - 40 keV	
max. counting rate	1 000 000 cps	
concentration range	from 1 ppm to 100%	

Radiography

Point detector of transmitted through the sample radiation for radiographic studies (optionally CCD detector)

Analytical unit	
Power supply	230 V, 50 Hz
Size (W x D x H)	615 x 665 x 650 mm
Weight	85 kg

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